

GS3M4517K

1700 V 45 mΩ SiCMOSFET

Silicon Carbide MOSFET
N-Channel Enhancement Mode

V_{DS}	=	1700 V
$R_{DS(ON)(Typ.)}$	=	45 mΩ
$I_D (T_C = 100^\circ\text{C})$	=	41 A

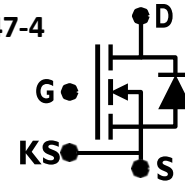
Features

- GS3M™ SiC MOSFET Technology
- Superior $Q_G \times R_{DS(ON)}$ Figure of Merit
- Low Capacitances and Low Gate Charge
- High V_{th} for Increased System Stability
- Fast and Reliable Body Diode
- High Avalanche and Short Circuit Ruggedness
- Low Conduction Losses at High Temperatures
- Optimized Package with Separate Driver Source Pin

Package



TO-247-4



D = Drain
G = Gate
S = Source
KS = K Ivin S r



Advantages

- Increased Power Density for Compact System
- High Frequency Switching
- Reduced Losses for Higher System Efficiency
- Minimized Gate Ringing
- Improved Thermal Capabilities
- High Cost-Performance Index
- Ease of Paralleling without Thermal Runaway
- Simple to Drive

Applications

- Electric Vehicle Fast Charging
- Solar Inverters
- Traction Inverters
- Smart Grid and HVDC
- High Voltage DC-DC Converters
- Switched Mode Power Supply
- Wind Energy Converters
- Pulsed Power

Absolute Maximum Ratings (At $T_C = 25^\circ\text{C}$ Unless Otherwise Stated)

Parameter	Symbol	Conditions	Values	Unit	Note
Drain-Source Voltage	$V_{DS(max)}$	$V_{GS} = 0\text{ V}, I_D = 100\text{ }\mu\text{s}$	1700	V	
Gate-Source Voltage (Dynamic)	$V_{GS(max)}$		-10 / +25	V	
Gate-Source Voltage (Static)	$V_{GS(op)}$	Recommended Operation	-5 / +20	V	
Continuous Forward Current	I_D	$T_C = 100^\circ\text{C}, V_{GS} = 20\text{ V}$	41	A	Fig. 14
		$T_C = 135^\circ\text{C}, V_{GS} = 20\text{ V}$	30		
Pulsed Drain Current	$I_{D(pulse)}$	$t_P \leq 10\text{ }\mu\text{s}, D \leq 1\%, \text{ Note 1}$	140	A	Fig. 13
Power Dissipation	P_D	$T_C = 25^\circ\text{C}$	256	W	Note 2
Operating and Storage Temperature	T_j, T_{stg}		-55 to 175	$^\circ\text{C}$	

Note 1: Pulse Width t_P Limited by $T_{j(max)}$

Note 2: Assuming $R_{thJC(max)} = 0.59^\circ\text{C/W}$

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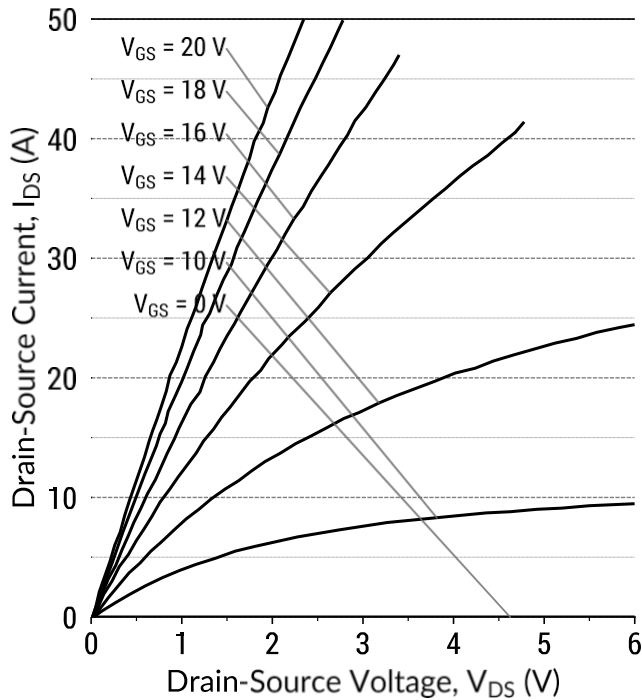
Electrical Characteristics (At $T_C = 25^\circ\text{C}$ Unless Otherwise Stated)

Parameter	Symbol	Conditions	Values			Unit	Note
			Min.	Typ.	Max.		
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}, I_D = 100\text{ }\mu\text{A}$	1700			V	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 1700\text{ V}, V_{GS} = 0\text{ V}$		1		μA	
Gate Source Leakage Current	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = 20\text{ V}$			100	nA	
		$V_{DS} = 0\text{ V}, V_{GS} = -10\text{ V}$			-100		
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 10\text{ mA}$	3.3	4		V	Fig. 9
		$V_{DS} = V_{GS}, I_D = 10\text{ mA}, T_j = 175^\circ\text{C}$		3			
Transconductance	g_{fs}	$V_{DS} = 10\text{ V}, I_D = 35\text{ A}, T_j = 175^\circ\text{C}$		9.3		S	Fig. 4
		$V_{DS} = 10\text{ V}, I_D = 35\text{ A}, T_j = 175^\circ\text{C}$		7.7			
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 20\text{ V}, I_D = 35\text{ A}, T_j = 175^\circ\text{C}$		45	54	mΩ	Fig. 5-8
		$V_{GS} = 20\text{ V}, I_D = 35\text{ A}, T_j = 175^\circ\text{C}$		76			
Input Capacitance	C_{iss}			2693			
Output Capacitance	C_{oss}			99		pF	Fig. 10
Reverse Transfer Capacitance	C_{rss}	$V_{DS} = 1000\text{ V}, V_{GS} = 0\text{ V}$		17.3			
C_{oss} Stored Energy	E_{oss}	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$		113		μJ	Fig. 11
C_{oss} Stored Charge	Q_{oss}			175		nC	
Internal Gate Resistance	$R_{G(int)}$	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$		1.5Ω			

Reverse Diode Characteristics

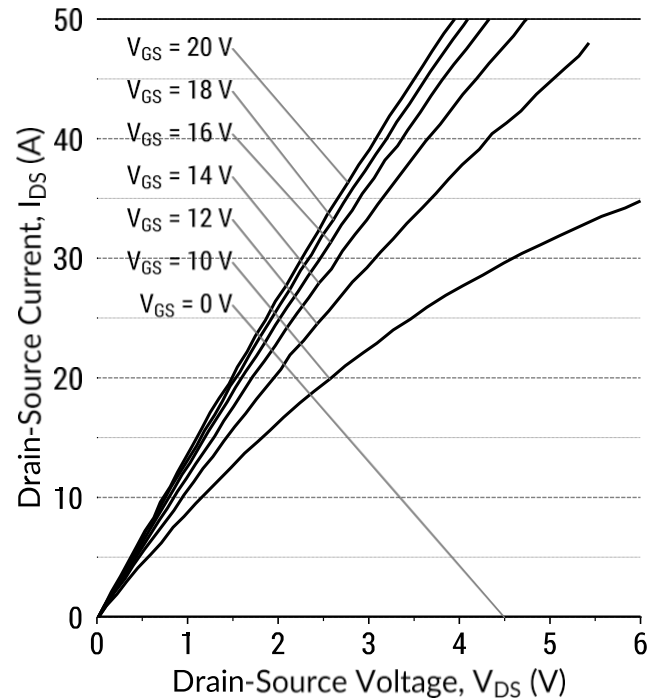
Parameter	Symbol	Conditions	Values			Unit	Note
			Min.	Typ.	Max.		
Diode Forward Voltage	V_{SD}	$V_{GS} = -5\text{ V}, I_{SD} = 17\text{ A}$		4		V	Fig. 12-13
		$V_{GS} = -5\text{ V}, I_{SD} = 17\text{ A}, T_j = 175^\circ\text{C}$		3.5			
Continuous Diode Forward Current	I_S	$V_{GS} = -5\text{ V}, T_C = 100^\circ\text{C}$		28		A	
Diode Pulse Current	$I_{S(pulse)}$	$V_{GS} = -5\text{ V}, \text{Note 1}$		140		A	

Figure 1: Output Characteristics ($T_j = 25^\circ\text{C}$)



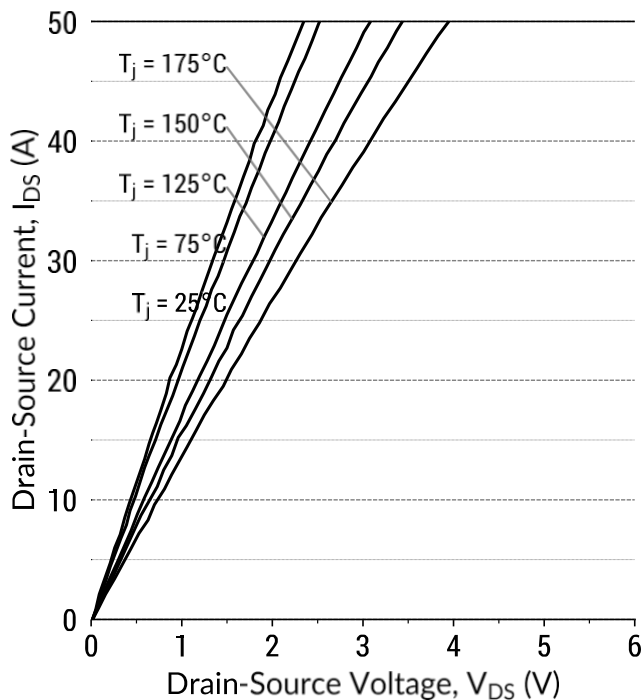
$$I_D = f(V_{DS}, V_{GS}); t_P = 250\mu\text{s}$$

Figure 2: Output Characteristics ($T_j = 175^\circ\text{C}$)



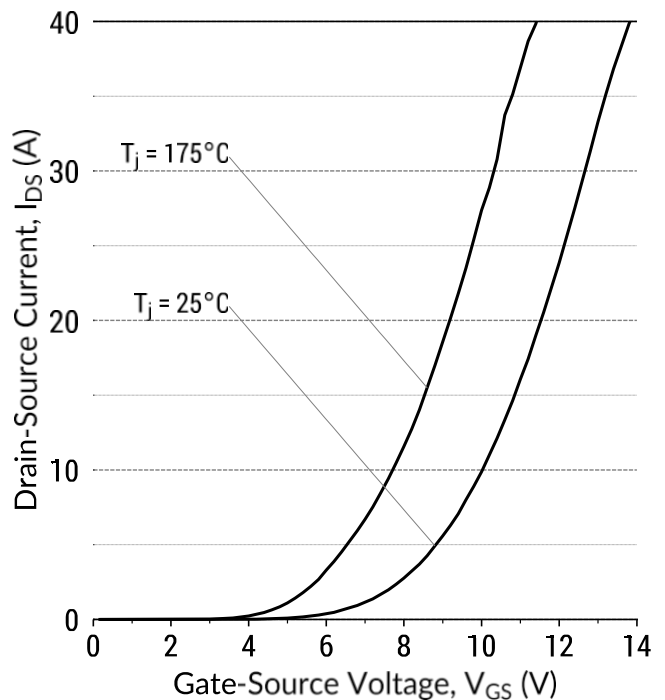
$$I_D = f(V_{DS}, V_{GS}); t_P = 250\mu\text{s}$$

Figure 3: Output Characteristics ($V_{GS} = 20\text{ V}$)



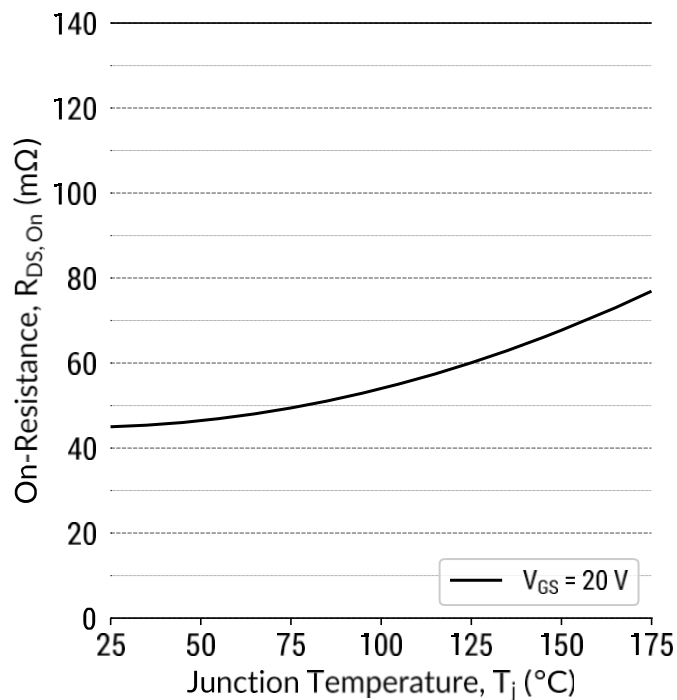
$$I_D = f(V_{DS}, T_j); t_P = 250\mu\text{s}$$

Figure 4: Transfer Characteristics ($V_{DS} = 10\text{ V}$)



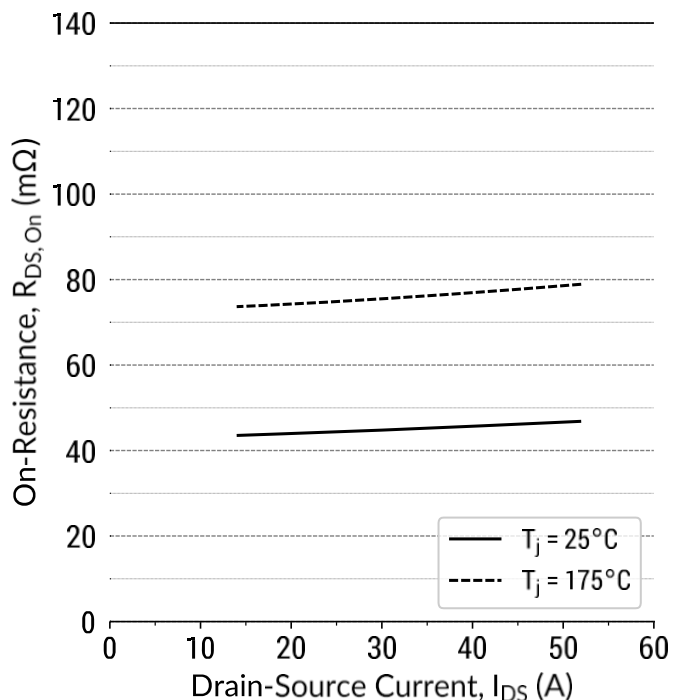
$$I_D = f(V_{GS}, T_j); t_P = 100\mu\text{s}$$

Figure 5: On-State Resistance v/s Temperature



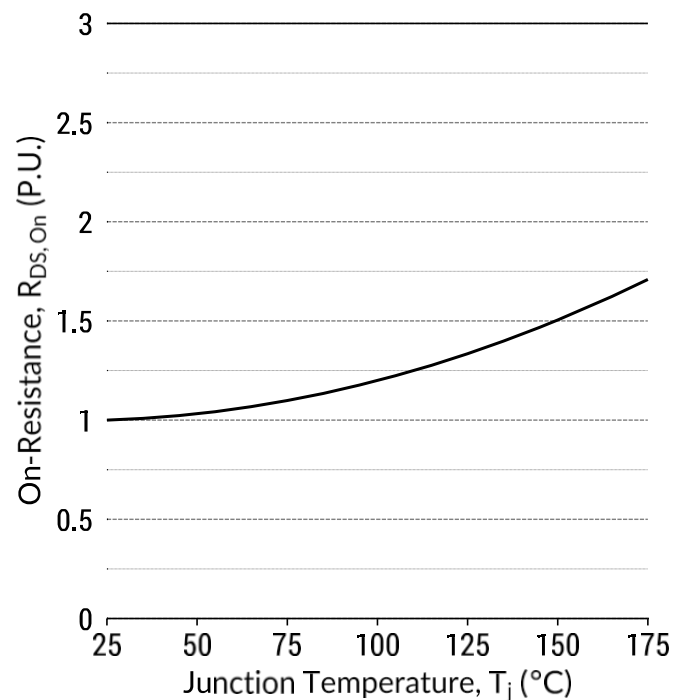
$$R_{DS(ON)} = f(T_j, V_{GS}); t_P = 250 \mu s; I_D = 35 A$$

Figure 6: On-State Resistance v/s Drain Current



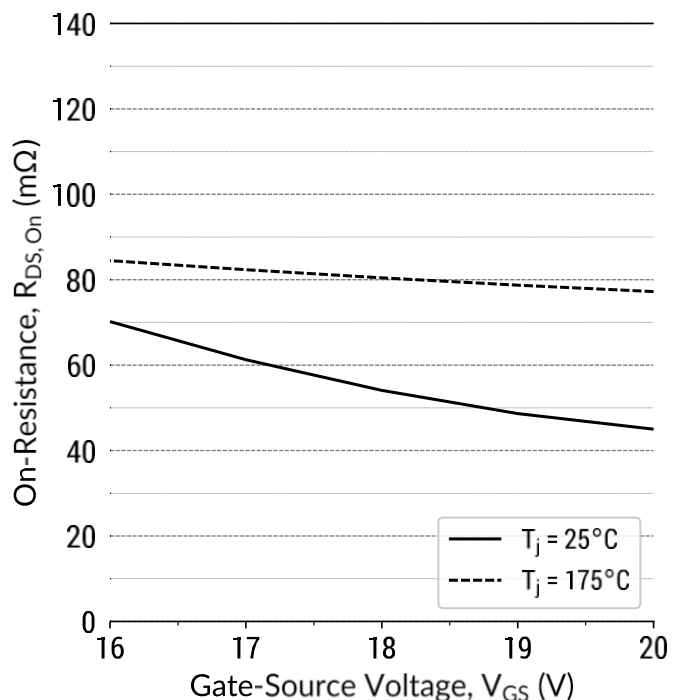
$$R_{DS(ON)} = f(T_j, I_D); t_P = 250 \mu s; V_{GS} = 20$$

Figure 7: Normalized On-State Resistance v/s Temperature



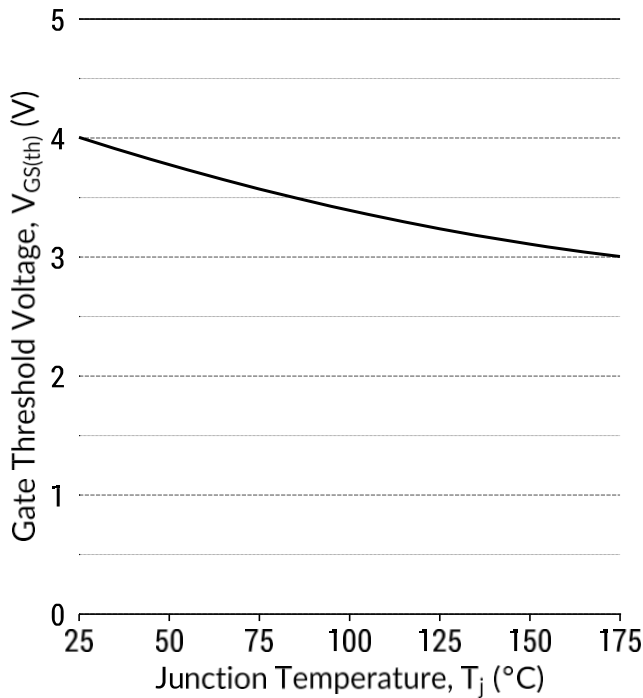
$$R_{DS(ON)} = f(T_j); t_P = 250 \mu s; I_D = 35 A; V_{GS} = 20 V$$

Figure 8: On-State Resistance v/s Gate Voltage



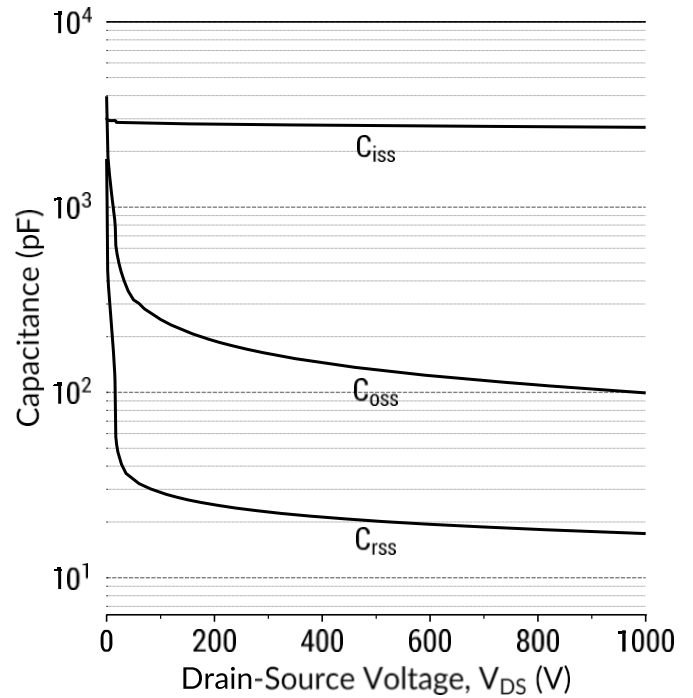
$$R_{DS(ON)} = f(T_j, V_{GS}); t_P = 250 \mu s; I_D = 35$$

Figure 9: Threshold Voltage Characteristics



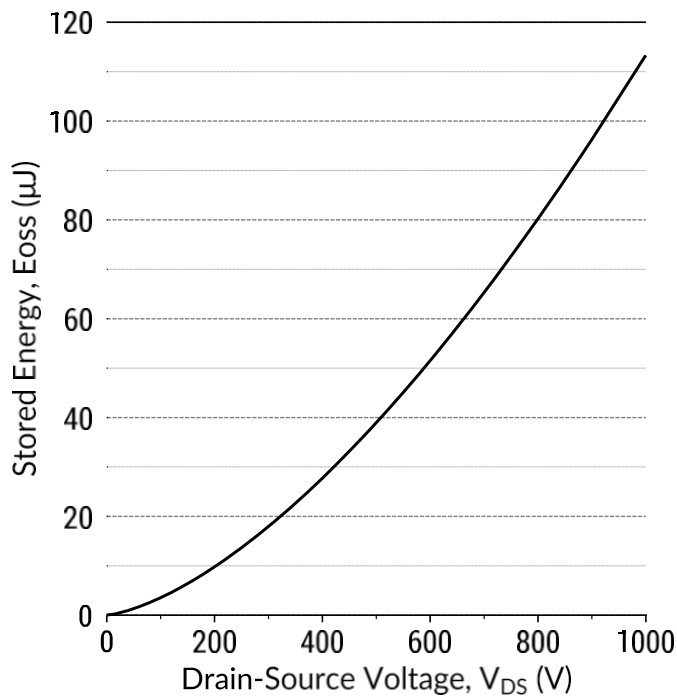
$$V_{GS(th)} = f(T_j); V_{DS} = V_{GS}; I_D = 10$$

Figure 10: Capacitance v/s Drain-Source Voltage



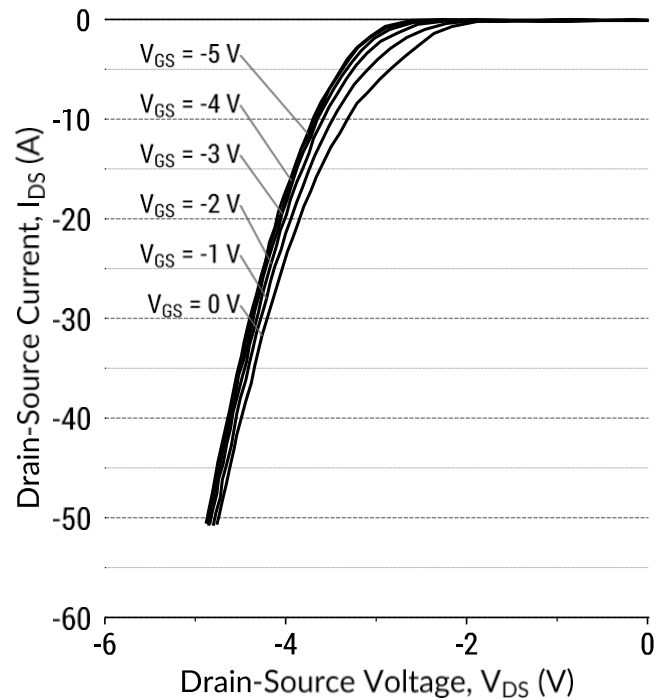
$$f = 1\text{MHz}; V_{AC} = 25\text{mV}$$

Figure 11: Output Capacitor Stored Energy



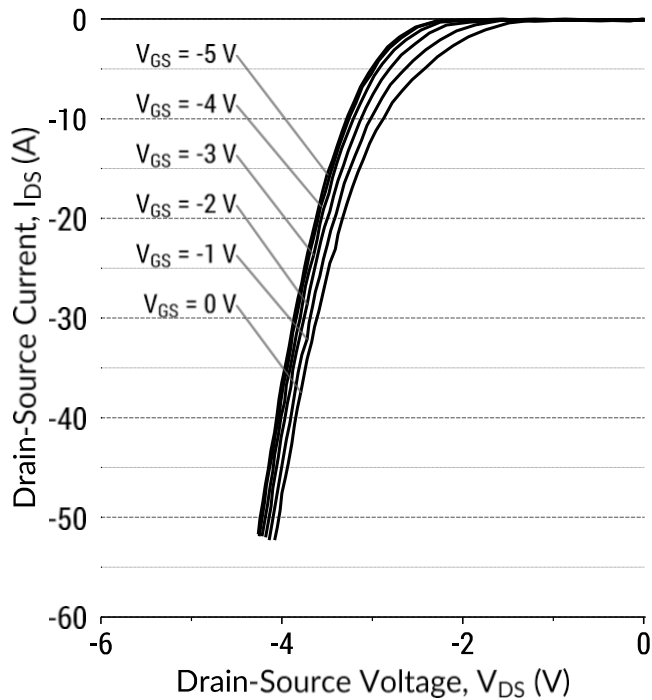
$$E_{oss} = f(V_{DS})$$

Figure 12: Body Diode Characteristics ($T_j = 25^\circ\text{C}$)



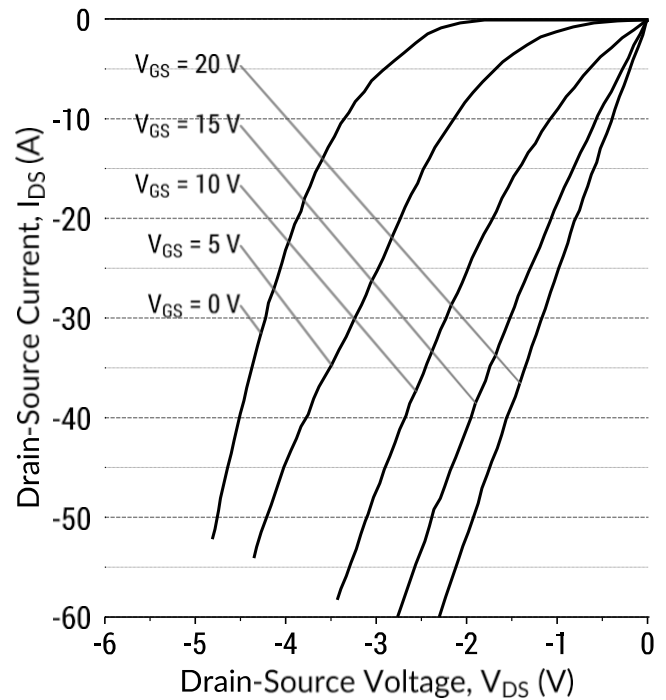
$$I_D = f(V_{DS}, V_{GS}); t_P = 250\mu\text{s}$$

Figure 13: Body Diode Characteristics ($T_j = 175^\circ\text{C}$)



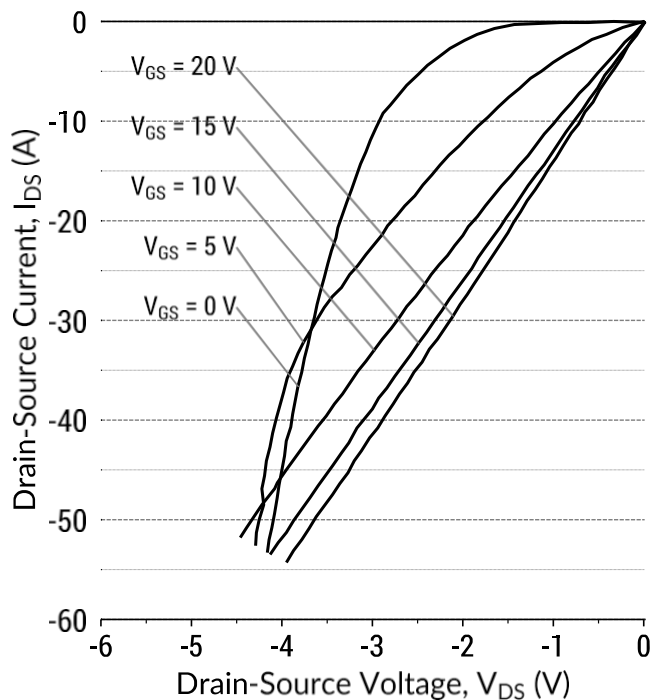
$$I_D = f(V_{DS}, V_{GS}); t_P = 250\mu\text{s}$$

Figure 14: Third Quadrant Characteristics ($T_j = 25^\circ\text{C}$)



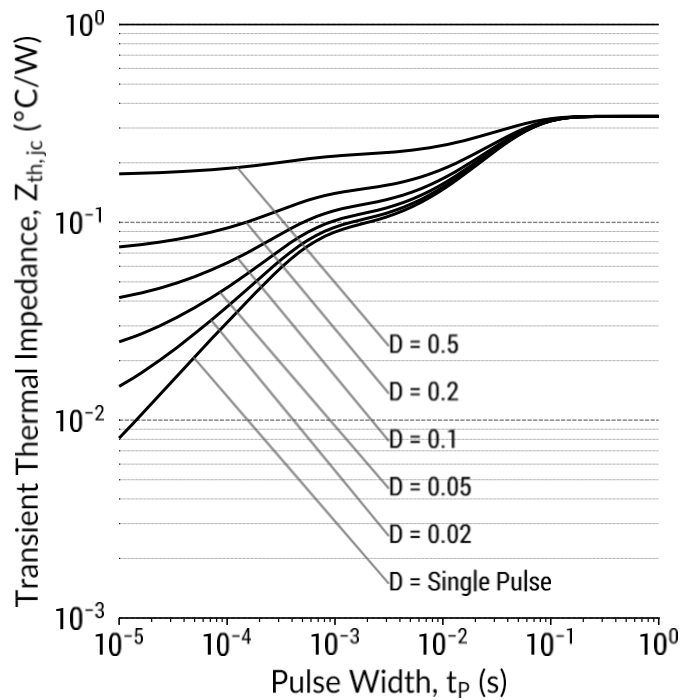
$$I_D = f(V_{DS}, V_{GS}); t_P = 250\mu\text{s}$$

Figure 15: Third Quadrant Characteristics ($T_j = 175^\circ\text{C}$)



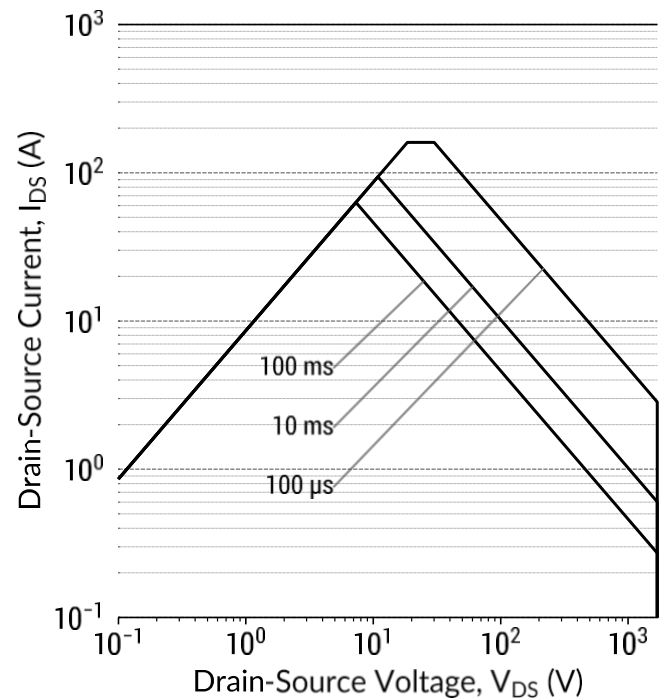
$$I_D = f(V_{DS}, V_{GS}); t_P = 250\mu\text{s}$$

Figure 16: Transient Thermal Impedance



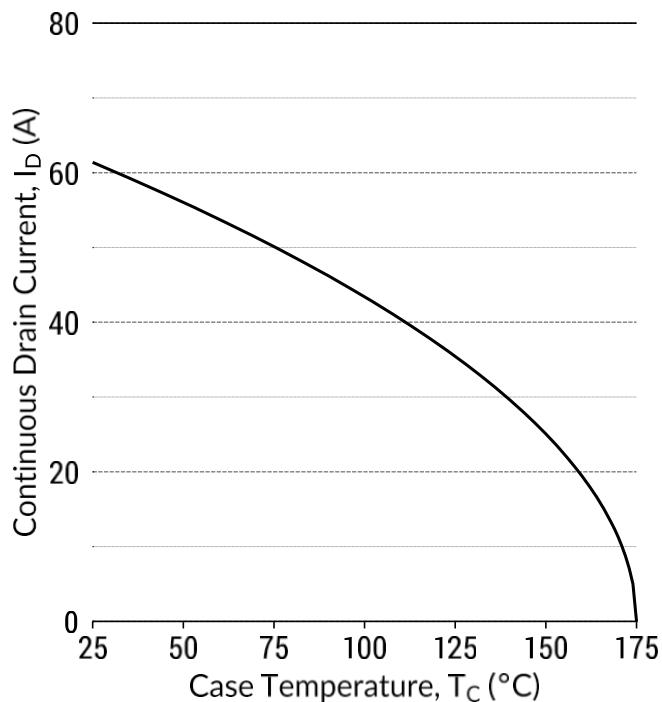
$$Z_{th,jc} = f(t_p, D); D = t_p / T$$

Figure 17: Safe Operating Area ($T_c = 25^{\circ}\text{C}$)



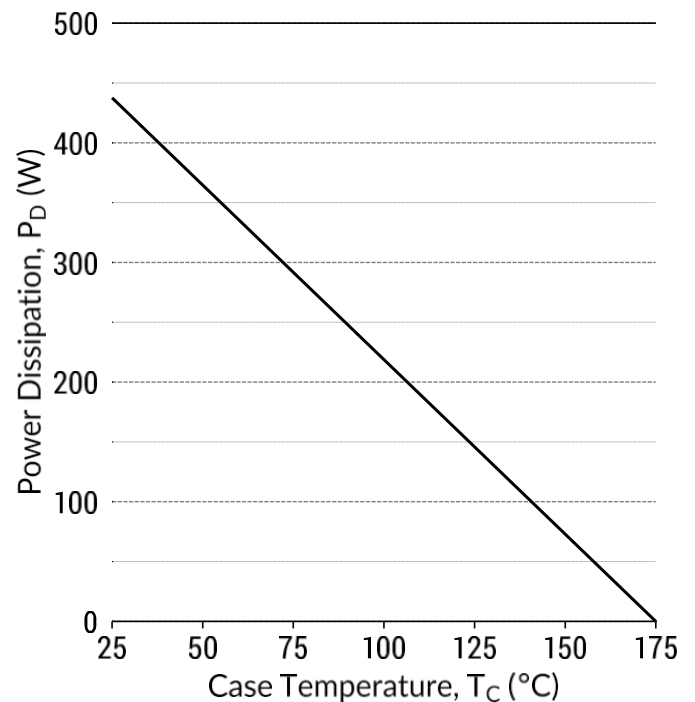
$$I_D = f(V_{DS}, t_p); T_j \leq 175^{\circ}\text{C}; D = 0$$

Figure 18: Current De-rating Curve



$$I_D = f(T_C); T_j \leq 175^{\circ}\text{C}$$

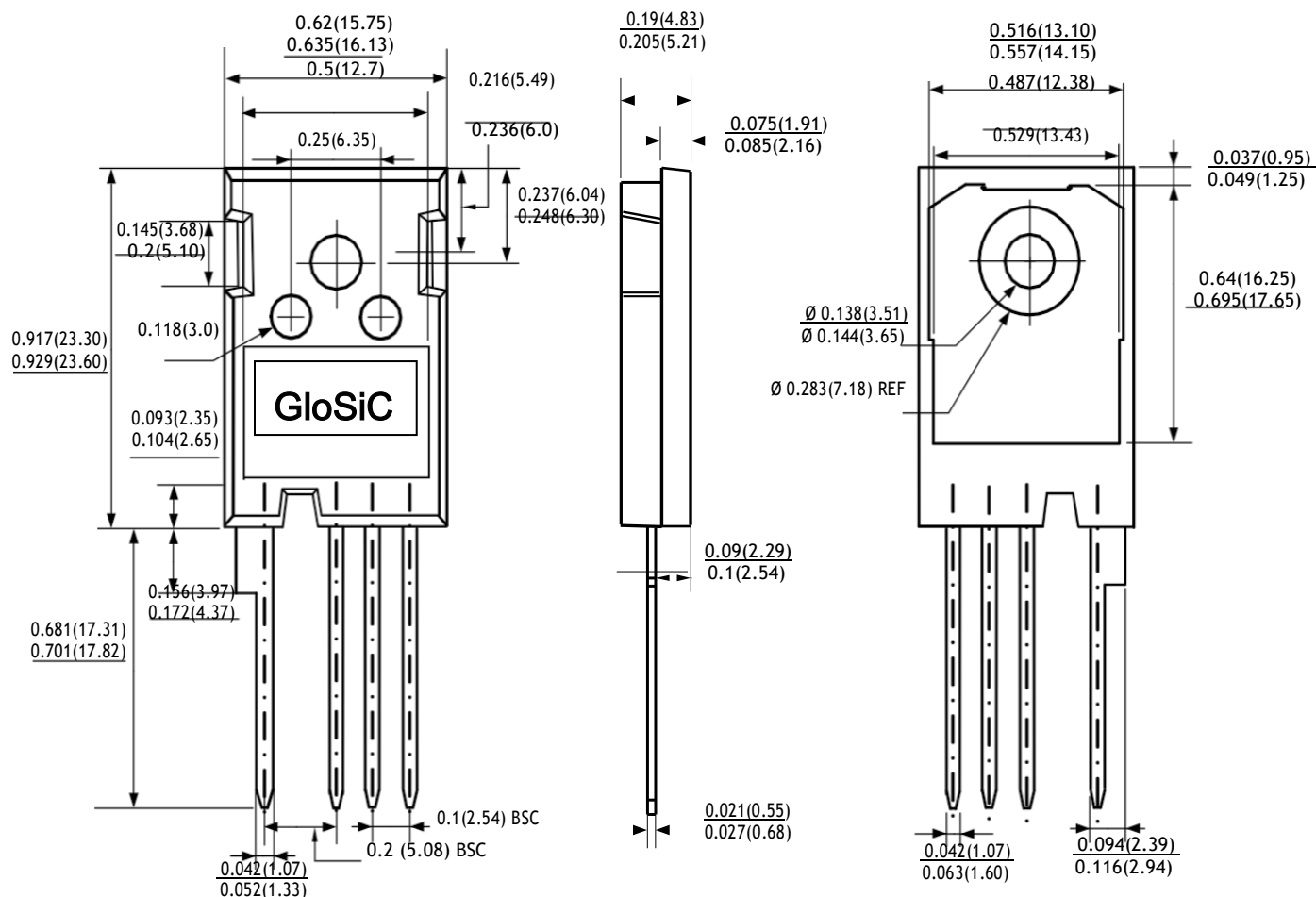
Figure 19: Power De-rating Curve



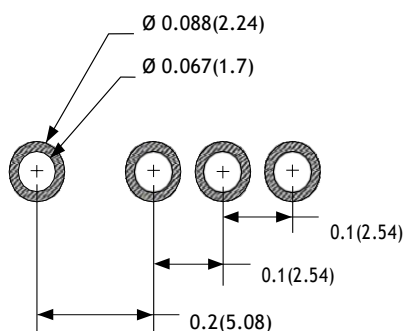
$$P_D = f(T_C); T_j \leq 175^{\circ}\text{C}$$

Package Dimensions

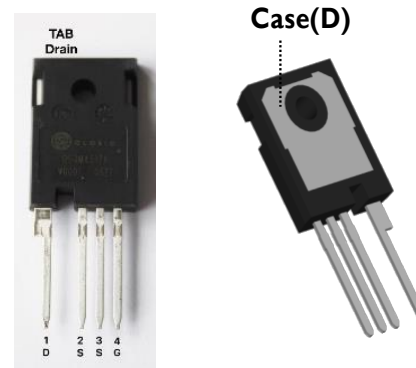
TO-247-4 Package Outline



Recommended Solder Pad Layout



Package View



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NOTE

2. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
3. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUS

RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS 2), as adopted by EU member states on January 2, 2013 and amended on March 31, 2015 by EU Directive 2015/863. RoHS Declarations for this product can be obtained from your GloSiC representative.

REACH Compliance

REACH substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact a GloSiC representative to insure you get the most up-to-date REACH SVHC Declaration. REACH banned substance information (REACH Article 67) is also available upon request.

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical equipment, aircraft navigation or communication or control systems, or air traffic control systems.